2SK3560

Silicon N-channel power MOSFET

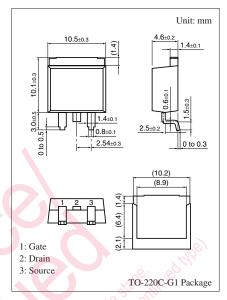
For PDP/For high-speed switching

■ Features

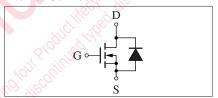
- Low on-resistance, low Q_g
- High avalanche resistance

■ Absolute Maximum Ratings $T_C = 25$ °C

Parameter		Symbol	Rating	Unit
Drain-source surrender voltage		V _{DSS}	230	V
Gate-source surrender voltage		V _{GSS}	±30	V
Drain current		I_D	30	A
Peak drain current		I_{DP}	120	A
Power		P_{D}	50	W
dissipation	$T_a = 25$ °C		3	
Channel temperature		T _{ch}	150	°C
Storage temperature		T_{stg}	-55 to +150	°C



Internal Connection



■ Electrical Characteristics $T_C = 25$ °C ± 3 °C

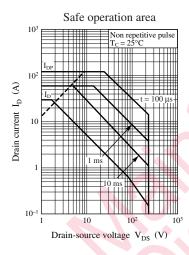
Parameter	Symbol	Conditions	Min	Тур	Max	Unit
Gate-drain surrender voltage	V _{DSS}	$I_D = 1 \text{ mA}, V_{GS} = 0$	230			V
Diode forward voltage	V _{DSF}	$I_{DR} = 30 \text{ A}, V_{GS} = 0$			-1.5	V
Gate threshold voltage	V _{th}	$V_{DS} = 25 \text{ V}, I_{D} = 1 \text{ mA}$	2		4	V
Drain-source cutoff current	I_{DSS}	$V_{DS} = 184 \text{ V}, V_{GS} = 0$			100	μΑ
Gate-source cutoff currentt	I _{GSS}	$V_{GS} = \pm 30 \text{ V}, V_{DS} = 0$			±1	μΑ
Drain-source on resistance	R _{DS(on)}	$V_{GS} = 10 \text{ V}, I_D = 15 \text{ A}$		55	74	mΩ
Forward transfer admittance	Y _{fs}	$V_{DS} = 25 \text{ V}, I_D = 15 \text{ A}$	8	19		S
Short-circuit forward transfer capacitance (Common-source)	C _{iss}	$V_{DS} = 25 \text{ V}, V_{GS} = 0, f = 1 \text{ MHz}$		2330		pF
Short-circuit output capacitance (Common-source)	C _{oss}			356		pF
Reverse transfer capacitance (Common-source)	C _{rss}			44		pF
Turn-on delay time	t _{d(on)}	$V_{DD} \approx 100 \text{ V}, I_D = 15 \text{ A}$		39		ns
Rise time	t _r	$R_L \approx 6.7 \ \Omega, \ V_{GS} = 10 \ V$		37		ns
Turn-off delay time	t _{d(off)}			221		ns
Fall time	t _f			46		ns
Reverse recovery time	t _{rr}	$L = 230 \mu H, V_{DD} = 100 V$		164		ns
Reverse recovery charge	Q _{rr}	$I_{DR} = 15 \text{ A}, \text{ di /dt} = 100 \text{ A/ } \mu\text{s}$		853		nC

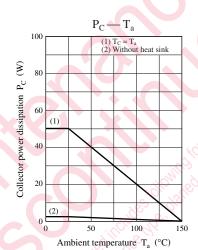
Note) Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 measuring methods for transistors.

■ Electrical Characteristics (Continued) $T_C = 25$ °C ± 3 °C

Parameter	Symbol	Conditions	Min	Тур	Max	Unit
Total gate charge	Qg	$V_{DD} = 100 \text{ V}, I_D = 25 \text{ A}$		51.2		nC
Gate-source charge	Q_{gs}	$V_{GS} = 10 \text{ V}$		8.2		nC
Gate-drain charge	Q_{gd}			19.4		nC
Channel-case heat resistance	R _{th(ch-c)}				2.5	°C/W
Channel-atmosphere heat resistance	R _{th(ch-a)}				89.2	°C/W

Note) Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 measuring methods for transistors.





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